AMENDMENTS TO THE CLAIMS

This listing of claims will replace all prior versions, and listings, of claims in the Application:

Listing of Claims:

1. (Currently amended) Analytical system for determining an analyte in a sample, the system comprising

a detection unit for detecting at least one signal that has been changed by an analyte in a sample and

an evaluation unit to determine at least one analyte in the sample based on the at least one signal and

a transport unit with a contact area wherein the contact area is suitable for directly or indirectly contacting the analytical system with a test element on which the sample can be applied and the transport unit comprises at least one piezoelectric element which vibrates the contact area of the transport unit and the test element is transported along a defined transport path in the analytical system as soon as the contact area of the transport unit is directly or indirectly contacted with a test element and the contact area is vibrated by the at least one piezoelectric element, wherein the test element comprises a carrier and an evaluation area on which the sample is applied, and wherein the contact area of the transport unit and the carrier of the test element are made such that in a resting state of the transport unit static frictional forces act between the contact area and the carrier to such an extent that the test element is fixed in position relative to the transport unit.

2. (Cancelled) Analytical system as claimed in claim 1, which is used to analyse the test element wherein the test element comprises a carrier and an evaluation area on which the sample is applied.

3. (Original) Analytical system as claimed in claim 1, in which the test element is present in a magazine housing.

4. (Original) Analytical system as claimed in claim 1, in which a detection site is located in the analytical system along the transport path.

5. (Original) Analytical system as claimed in claim 1, comprising at least two piezoelectric elements that are electronically actuated independently of one another.

6. (Original) Analytical system as claimed in claim 1, in which the piezoelectric element is contacted with a detector and the detector is used to control the at least one piezoelectric element.

7. (Original) Analytical system as claimed in claim 6, in which the detector is a component of the detection unit.

8. (Original) Analytical system as claimed in claim 6, in which the detector detects the evaluation area of a test element.

9. (Cancelled) Analytical system as claimed in claim 2, in which the contact area of the transport unit and the carrier of the test element are made such that in a resting state of the transport unit static frictional forces act between the contact area and the carrier to such an extent that the test element is fixed in position relative to the transport unit.

10. (Original) Analytical system as claimed in claim 1, in which the transport unit has a contact sensor which activates the transport unit when the test element contacts the contact area of the transport unit.

11. (Original) Analytical system as claimed in claim 1, in which the transport unit causes a carrier element to rotate which is suitable for bearing and positioning a reel.

12. (Original) Analytical system as claimed in claim 11, which is suitable for using a test strip tape wound onto the reel.

13. (Currently amended) Method for transporting a test element in an analytical system comprising

contacting a test element directly or indirectly with a contact area of a transport unit in an analytical system, and prior thereto or subsequently

activating a piezoelectric element of the transport unit such that the contact area of the transport unit is vibrated,

transporting the test element due to the vibrated contact area along a predetermined transport path in the analytical system and

stopping the transport process of the test element such that the test element is positioned at a predetermined site in the analytical system, wherein the test element comprises a carrier and an evaluation area on which a sample is applied, and wherein the contact area of the transport unit and the carrier of the test element are made such that in a resting state of the transport unit static frictional forces act between the contact area and the carrier to such an extent that the test element is fixed in position relative to the transport unit.

14. (Original) Method as claimed in claim 13, in which the test element is positioned relative to a detection site of a detection unit of the analytical system.

15. (Original) Method as claimed in claim 13, in which the test element is returned into a magazine.

16. (Original) Method as claimed in claim 13, wherein the analytical system comprises a detection unit for detecting at least one signal that has been changed by an analyte in a sample and an evaluation unit to determine at least one analyte in the sample based on the at least one signal and the transport unit with the contact area wherein the contact area is suitable for directly or indirectly contacting the analytical system with a

test element on which the sample can be applied and the transport unit comprises at least one piezoelectric element which vibrates the contact area of the transport unit and the test element is transported along a defined transport path in the analytical system as soon as the contact area of the transport unit is directly or indirectly contacted with a test element and the contact area is vibrated by the at least one piezoelectric element.

17. (Currently amended) Analytical system for determining an analyte in a sample, the system comprising

a detection unit for detecting at least one signal that has been changed by an analyte in a sample,

an evaluation unit to determine at least one analyte in the sample based on the at least one signal, and

a transport unit with a contact area wherein the contact area is suitable for direct or indirect contact with a test element on which the sample can be applied and the transport unit comprises at least one piezoelectric element which vibrates the contact area of the transport unit and the test element is transported along a defined transport path in the analytical system as soon as the contact area of the transport unit is directly or indirectly contacted with a test element and the contact area is vibrated by the at least one piezoelectric element, wherein the transport of the test element is formed to be stopped such that the test element is positioned at a predetermined site in the analytical system, wherein the test element comprises a carrier and an evaluation area on which the sample is applied, and wherein the contact area of the transport unit and the carrier of the test element are made such that in a resting state of the transport unit static frictional forces act between the contact area and the carrier to such an extent that the test element is fixed in position relative to the transport unit.

Claims 18-33 (Cancelled).